

Quantum metrology in the finite-sample regime

JOHANNES JAKOB MEYER
FU BERLIN

BEYOND IID 2023
 @jj_xyz

Based on arXiv:2307.06370

Quantum metrology in the finite-sample regime

Johannes Jakob Meyer,¹ Sumeet Khatri,¹ Daniel Stilck França,^{1,2,3} Jens Eisert,^{1,4,5} and Philippe Faist¹

¹*Dahlem Center for Complex Quantum Systems, Freie Universität Berlin, 14195 Berlin, Germany*

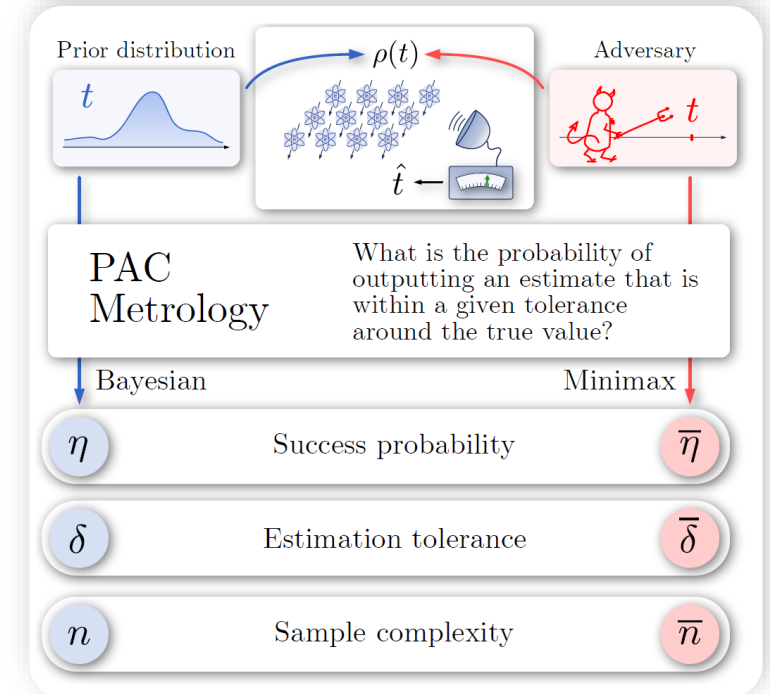
²*Department of Mathematical Sciences, University of Copenhagen, 2100 København, Denmark*

³*Ecole Normale Supérieure de Lyon, 69342 Lyon Cedex 07, France*

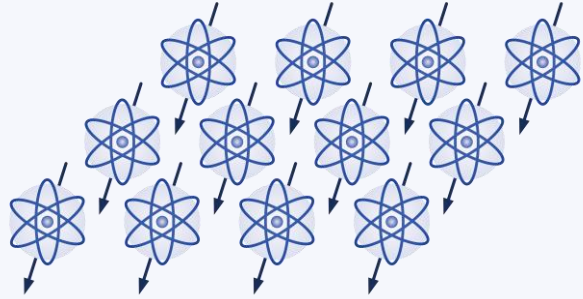
⁴*Helmholtz-Zentrum Berlin für Materialien und Energie, 14109 Berlin, Germany*

⁵*Fraunhofer Heinrich Hertz Institute, 10587 Berlin, Germany*

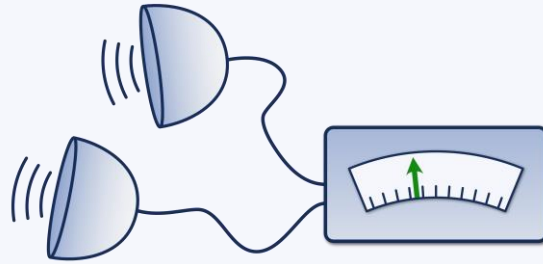
(Dated: July 14, 2023)



Traditional Quantum Metrology



$\rho(t)$



$Q(\hat{t})$

Want unbiased estimate

$$\mathbb{E}[\hat{t}] = t$$

with **low variance**

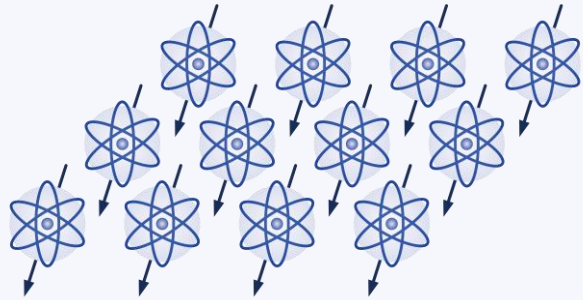
Cramér-Rao Bound

$$\text{Var}(\hat{t}) \geq \frac{1}{\mathcal{F}(t)}$$

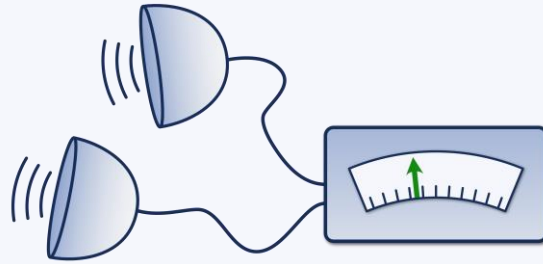
- › Inherently asymptotic
- › Assumes parameter is already approximately known
- › Application difficult to justify in the finite-sample regime

Single-shot Quantum M

Estimation Tolerance



$\rho(t)$



$Q(\hat{t})$

$$\text{Is } |t - \hat{t}| \leq \delta?$$

Yes →

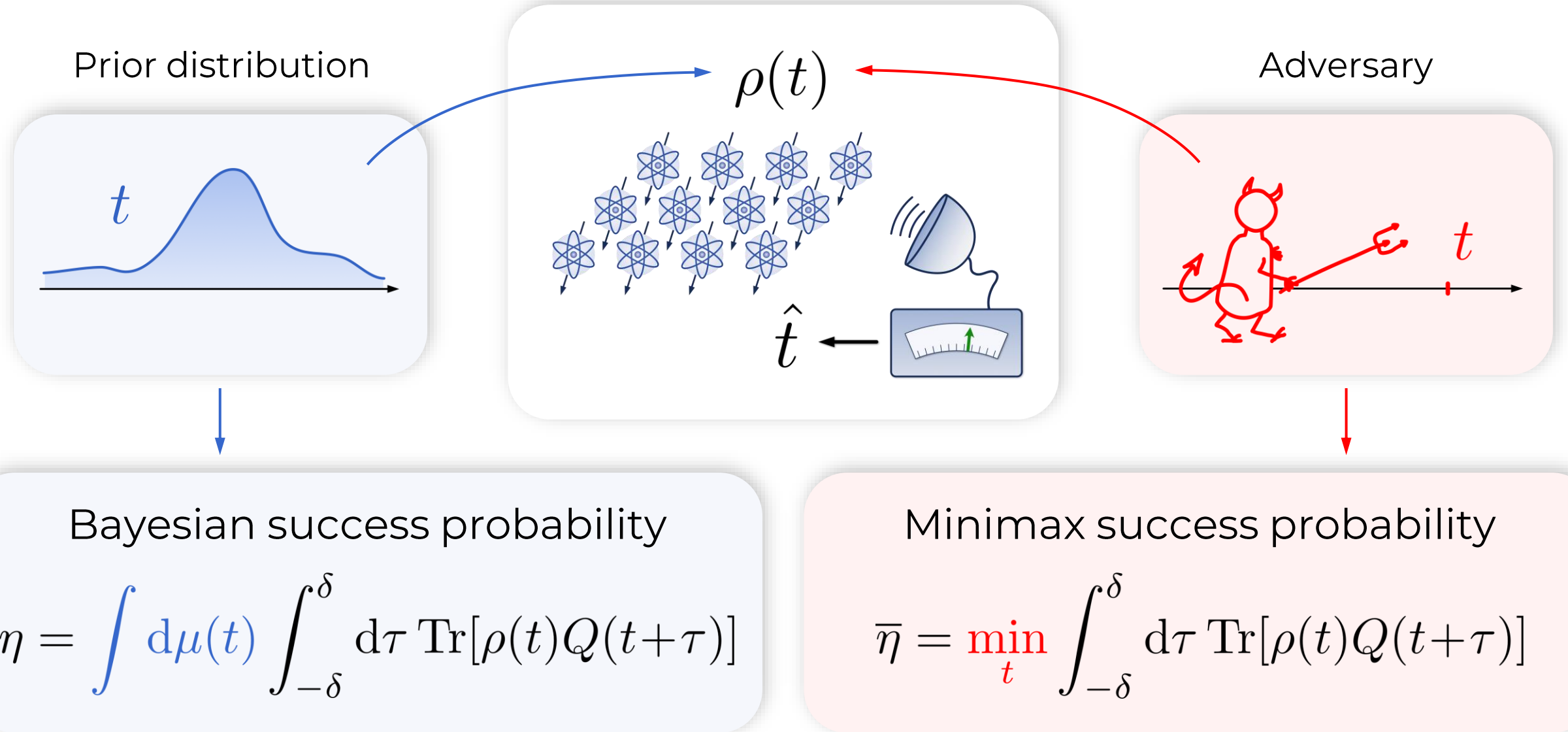
Success ✓

No →

Failure ✗


What is the probability of successful estimation?

Single-shot Quantum Metrology



Optimal Measurements

Optimal minimax success probability

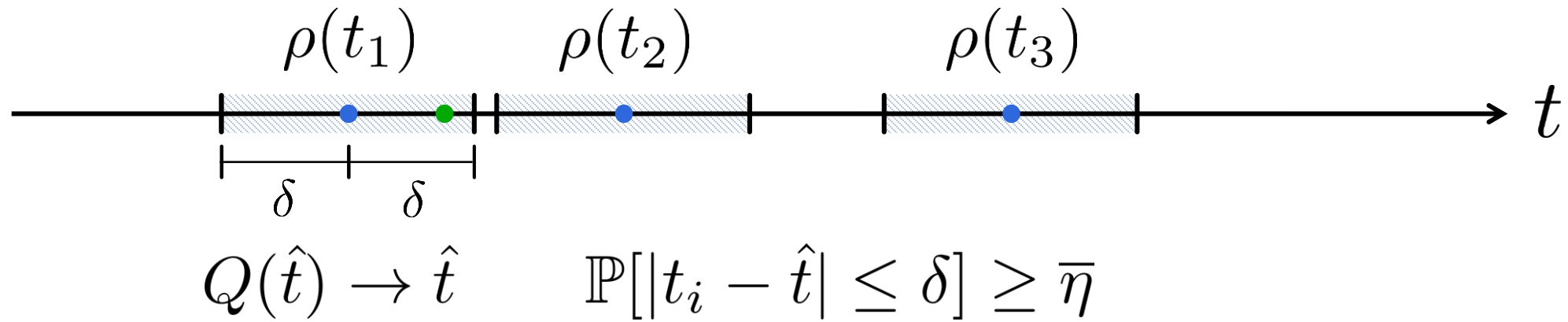
$$\bar{\eta}^* = \max_{Q(\hat{t})} \left\{ \min_t \int_{-\delta}^{\delta} d\tau \operatorname{Tr}[\rho(t)Q(t+\tau)] \right\}$$


Constitutes a **semi-infinite program**,
think a continuous semi-definite program

- › We give a dual formulation without duality gap
- › We generalize it to the parametrized channels where we optimize over combs or strategies with indefinite causal order
- › We also give post-processing strategies for fixed measurements

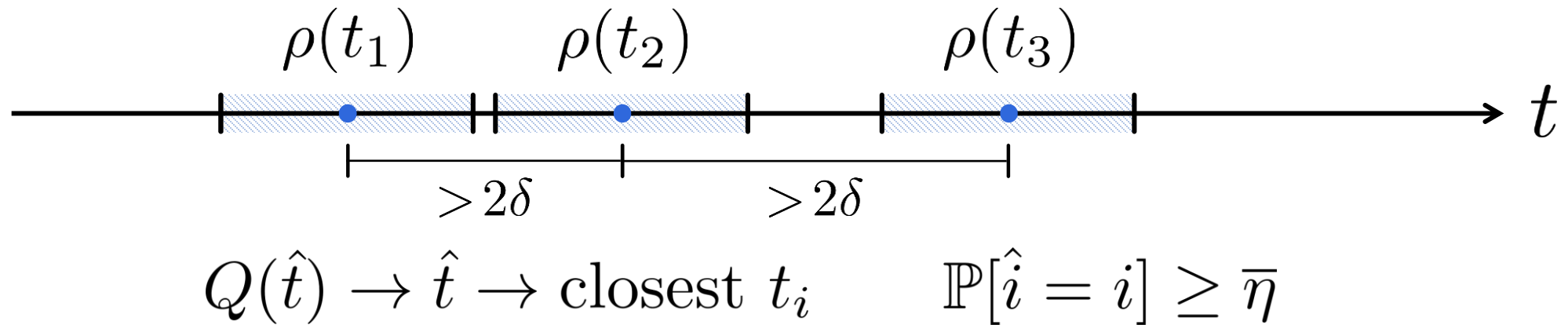
Connection to Hypothesis Testing

Metrology problem



Connection to Hypothesis Testing

Multi-hypothesis testing problem



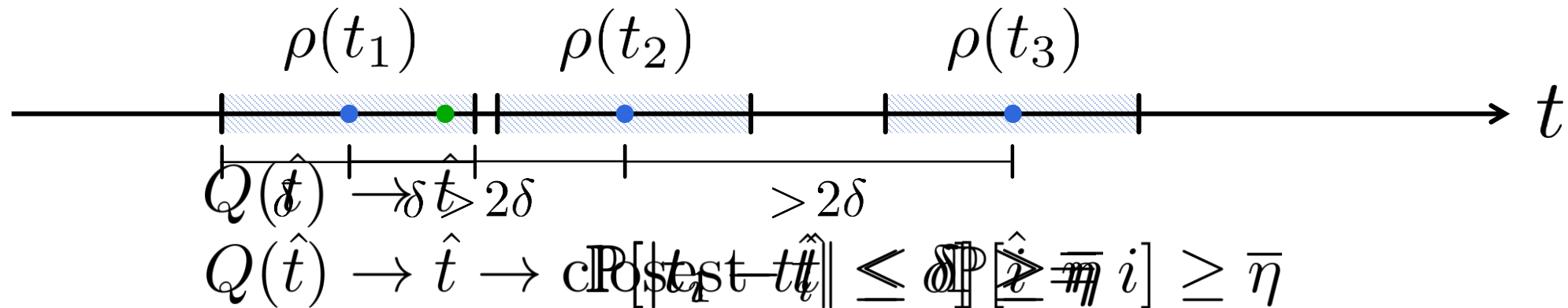
We conclude that

$$\bar{\eta} \leq \overline{P}_s(\{\rho(t_i)\}) \text{ as long as } |t_i - t_j| > 2\delta$$

Connection to Hypothesis Testing

Metrology problem

Multi-hypothesis testing problem



We conclude that

$$\bar{\eta} \leq \bar{P}_s(\{\rho(t_i)\}) \text{ as long as } |t_i - t_j| > 2\delta$$

Asymptotics

Asymptotic rate at constant tolerance

$$\overline{R}(\delta, \rho) := \lim_{n \rightarrow \infty} -\frac{1}{n} \log (1 - \overline{\eta}(\delta, \rho^{\otimes n}))$$

Hypothesis testing bound implies

$$\overline{R}(\delta, \rho) \leq \inf_{|t-t'| > 2\delta} C(\rho(t), \rho(t'))$$

Chernoff Divergence

$$C(\rho, \sigma) := - \inf_{0 \leq s \leq 1} \log \text{Tr}[\rho^s \sigma^{1-s}]$$

Asymptotics

We give the following achievable lower bound

$$\overline{R}(\delta, \rho) \geq \sup_{\{\mathcal{M}^{(n)}\}_{n \in \mathbb{N}}} \inf_{|t-t'| > 2\delta} \overline{R}(\rho(t), \rho(t'), \{\mathcal{M}^{(n)}\}_{n \in \mathbb{N}})$$

Hypothesis testing rate for a given measurement sequence

$$\overline{R}(\rho, \sigma, \{\mathcal{M}^{(n)}\}_{n \in \mathbb{N}}) := \lim_{n \rightarrow \infty} -\frac{1}{n} \log \left(\overline{P}_e(\mathcal{M}^{(n)}[\rho^{\otimes n}], \mathcal{M}^{(n)}[\sigma^{\otimes n}]) \right)$$

This allows us to compute the asymptotic rate in the commuting case

$$\overline{R}(\delta, \rho) = \inf_{|t-t'| > 2\delta} C(\rho(t), \rho(t')) \text{ if } [\rho(t), \rho(t')] = 0 \text{ for all } t, t'$$

Optimal Tolerance

So far, we analyzed the success probability at fixed tolerance. But in applications, we often care about the achievable precision at fixed success probability.

Minimax estimation tolerance

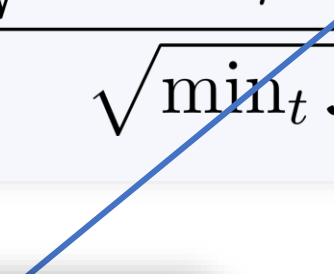
$$\bar{\delta}(\bar{\eta}) = \inf \left\{ \delta' \geq 0 \mid \bar{\eta} \leq \min_t \int_{-\delta'}^{\delta'} d\tau \operatorname{Tr}[\rho(t)Q(t+\tau)] \right\}$$

Finite-sample Cramér-Rao bound

Cramér-Rao bound

$$\sigma(\hat{t}) \geq \frac{1}{\sqrt{\mathcal{F}(t)}}$$

Our bound

$$\bar{\delta} \geq \frac{O\left(\sqrt{\log \frac{1}{1-\bar{\eta}}} - \boxed{q} \log \frac{1}{1-\bar{\eta}}\right)}{\sqrt{\min_t \mathcal{F}(t)}}$$


In the i.i.d. case

$$q = O\left(\frac{1}{\sqrt{n}}\right)$$

The PAC Metrology Framework

$\overline{\eta}$

SUCCESS PROBABILITY

What is the probability of obtaining an estimate within a fixed tolerance?

$\overline{\delta}$

ESTIMATION TOLERANCE

What is the smallest tolerance that still guarantees a fixed success probability?

\overline{n}

SAMPLE COMPLEXITY

How many copies of a state do I need to guarantee a fixed success probability and tolerance?

Further Results in the Paper

- › We perform a finite-sample analysis of phase estimation
- › We connect our quantities to single-shot entropy measures
- › We lift the hypothesis testing connection to quantum channels with different access models
- › We discuss many possible extensions of our results and definitions, e.g. the multi-parameter case
- › We give an overview of open questions

Open Questions

- › What measurements (i.e. POVMs) give good out-of-the-box performance guarantees? Pretty good measurement?
- › Improved finite-sample analogues of the Cramér-Rao bound
- › Understanding the advantages of adaptive processing and entanglement
- › Can we prove general achievability for the asymptotic rate presented in this talk?
- › What are the admissible scalings with mixed asymptotics?

Summary

- › We give new tools to understand quantum metrology in the single-shot regime
- › Our framework is very close to quantum information theory both in tools as in results
- › A plethora of open questions ranging from practically oriented to completely information-theoretic
- › An exciting opportunity for quantum information theorists to make their mark on quantum metrology!

Thank you for your attention!



Slides



arXiv:2307.06370